Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/751,288	STEFANIK, JOHN R.	
Examiner	Art Unit	
ANNAN Q. SHANG	2623	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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updated search		2/25/2008	A.S